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International Standard IEC 61280-2-8 has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics.

The text of this standard is based on the following documents

FDIS	Report on voting
86C/485/FDIS	86C/505/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2

The committee has decided that the contents of this publication will remain unchanged until 2010. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES – **DIGITAL SYSTEMS -**



Part 2-8: Determination of low BER using Q-factor measurements

This part of IEC 61280 specifies two main methods for the determination of low BER values by making accelerated measurements. These include the variable decision threshold method (Clause 4) and the variable optical threshold method (Clause 5). In addition, a third method, the sinusoidal interference method, is described in Annex B.

2 Definitions and abbreviated terms

2.1 Definitions

For the purposes of this document, the following terms and definitions apply.

2.1.1 amplified spontaneous emission

ASE impairment generated in optical amplifiers

2.1.2 bit error ratio

BER

the number bits in error as a ratio of the total number of bits

2.1.3

intersymbol interference

ISI

mutual interference between symbols in a data stream, usually caused by non-linear effects and bandwidth limitations of the transmission path

2.1.4

Q-factor Q

ratio of the difference between the mean voltage of the 1 and 0 rails, and the sum of their 5_11_5 standard deviation values

2.2 Abbreviations

cw	Continuous wa	ve (normally	referring to a	sinusoidal wa	ave form)
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- DC Direct current
- DSO Digital sampling oscilloscope
- DUT Device under test
- PRBS Pseudo-random binary sequence